

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/809,659 | Applicant(s)/Patent Under Reexamination YACH ET AL. | |
| | Examiner Thao X. Le | Art Unit 2814 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-6,919,603 | 07-2005 | Brodsky et al. | 257/361 |
| | B | US-5,895,940 | 04-1999 | Kim, Dae-Gyu | 257/173 |
| | C | US-5,763,918 | 06-1998 | El-Kareh et al. | 257/355 |
| | D | US-5,691,557 | 11-1997 | Watanabe, Toshio | 257/357 |
| | E | US-6,891,230 | 05-2005 | Yu, Ta-Lee | 257/361 |
| | F | US-6,479,869 | 11-2002 | Hiraga, Noriaki | 257/350 |
| | G | US-6,535,368 | 03-2003 | Andresen et al. | 361/56 |
| | H | US-6,373,105 | 04-2002 | Lin, Shi-Tron | 257/357 |
| | I | US-6,594,132 | 07-2003 | Avery, Leslie Ronald | 361/111 |
| | J | US-6,826,026 | 11-2004 | Duvvury et al. | 361/56 |
| | K | US-6,891,207 | 05-2005 | Pequignot et al. | 257/173 |
| | L | US-6,441,439 | 08-2002 | Huang et al. | 257/355 |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.